

Notice of References Cited	Application/Control No. 09/617,036	Applicant(s)/Patent Under Reexamination PAIK ET AL.	
	Examiner Michael W. Hoyer	Art Unit 2614	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IEEE 100: The Authoritative Dictionary of IEEE Standards Terms, 2000, IEEE Press, 7 th ed., pages 1158-1159.
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